

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:

Emiko Nishida, et al.

Serial No.:

09/891,054

Filing Date:

June 25, 2001

Title:

Method and Apparatus for

Forming an Optical Multilayer

Filter

Art Unit: 1711

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November 26, 2002 San Francisco, California

Commissioner of Patents Washington, DC 20231

## INFORMATION DISCLOSURE STATEMENT

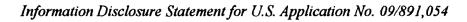
Sir:

Pursuant to the duty of disclosure set forth in 37 CFR § 1.56, Applicants respectfully submit the following information disclosure statement.

The undersigned certifies that each of the following references was contained in a communication from the EPO in a counterpart foreign application not more than three months prior to the filing of this statement.

The disclosed references are:

- C. Grèzes-Bessset, et al., "Synthesis and research of the optimum conditions for the optical monitoring of non-quarter-wave multilayers," Applied Optics, Optical Society of America, Washington, US, vol. 32, no. 28, Oct. 1, 1993, pages 5612-5618.
- S. Callard, et al., "New method for *in* situ control of Bragg reflector fabrication," Applied Physics Letters, American Institute of Physics, New York, US, vol. 68, no. 17, April 22, 1996, pages 2335-2336.
- M. Kildemo, et al., "A direct robust feedback method for growth control of optical coatings by multiwavelength ellipsometry," Thin Solid Films, Elsevier-Sequoia S.A. Lausanne, CH, vol. 313-314, Feb. 13, 1998, pages 484-489.



Applicants respectfully request that the Examiner initial the cited references shown on the enclosed form PTO-1449 and that the references be made of record in the present application.

Respectfully submitted,

Reg. No. 24,815

601 California St., Suite 1111 San Francisco, CA 94108-2805 Telephone: (415) 989-8080

Facsimile: (415) 989-0910

Cited references (3) Enc.

PTO Form 1449

Return receipt postcard

Certificate of Mailing Under 37 CFR 1.8

I certify that this Information Disclosure Statement and any enclosed materials are being deposited with the United States Postal Service on November 26, 2002 with sufficient postage as first class mail in an envelope addressed to Commissioner for Patents, Washington, DC 20231.

Thomas A. Gallagher

Docket: KPO108

DEC 0 2 2002 F

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

DOCKET KPO108 s.n. 09/891,054

INFORMATION DISCLOSURE STATEMENT

APPLICANT Emiko Nishida, et al.

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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP; draw line through citation if not in conformance

and not considered. Include copy of this form with next communication with applicant.